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PATENT

Attorney Docket No. 26822-0002 P2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#11

In re Application	)	
	)	
Inventor(s): LIANG, Rong-Chang, et al.	)	
	)	Art Unit: 2873
Application No.: 10/092,936	)	
	)	Examiner: TRA, Tuyen Q.
Filed: March 6, 2002	)	
	)	
Title: Electrophoretic Display and Novel	)	
Process for its Manufacture	)	

INFORMATION DISCLOSURE STATEMENT

Office of Petitions  
Crystal Plaza 4  
Suite 3C23  
Arlington, VA 22202

Sir:

Listed on an attached Form PTO-1449 is information known to applicant(s). This statement is being filed after payment of the issue fee, along with a Request for Continued Examination (RCE) and a preliminary amendment. The issue fee was paid by the Applicant on August 20, 2003.

Each of the references listed on the attached Form 1449 has been cited in related US Patent Applications. Applicants propose these documents for consideration for completeness in cross-citation within the related applications.

A copy of each listed publication and U.S. and foreign patent, except for pending non-published U.S. applications, has been provided in parent USSN 09/518,488, filed March 3, 2000. Therefore, a copy of each reference is not being submitted herewith. Applicant would be happy to provide the Examiner with a second copy upon request.

Applicants respectfully request that the information listed on the attached Form 1449 be considered by the Examiner and made of record in the above-identified application. The Examiner is requested to initial and return the enclosed Form 1449 substitute.

This statement is not intended to represent that a search has been made or that the information cited in the statement is, or is considered to be, material to patentability as defined in §1.56.

- ☒ This statement qualifies under 37 C.F.R. §1.97, subsection (b) because (check all that apply):
- ☐ (1) It is being filed within 3 months of the application filing date and is other than a continued prosecution application under § 1.53(d)  
-- OR --
- ☐ (2) It is being filed within 3 months of entry of a national stage  
-- OR --
- ☐ (3) It is being filed before the mail date of the first Office Action on the merits  
-- OR --
- ☒ (4) It is being filed before the mailing of a first Office Action after the filing of a request for continued examination under § 1.114.
- ☐ 37 C.F.R. §1.97(c). If this statement is being filed after the latest of: (1) three months beyond the filing date of a national application; (2) three months beyond the date of entry of the national stage as set forth in §1.491 in an international application; or (3) the mailing date of a first Office action on the merits, but before the mailing date of the earlier of a final office action under §1.113 or a notice of allowance under §1.311, then:
- ☐ a certification as specified in §1.97(e) is provided below; or
- ☐ a fee of \$180.00 as set forth in §1.17(p) is authorized below, enclosed, or included with the payment of other papers filed together with this statement.
- ☐ 37 C.F.R. §1.97(d). If this statement is being filed after the mailing date of the earlier of a final office action under §1.113 or a notice of allowance under §1.311, but before payment of the issue fee, then:
- A. a certification as specified in §1.97(e) is completed below; and
- B. a petition under 37 C.F.R. §1.97(d) requesting consideration of this statement is submitted herewith; and
- C. a fee of \$130.00 as set forth in §1.17(i)(1) is authorized below, enclosed, or included with the payment of other papers filed together with this statement.
- ☒ *Fee Authorization.* The Commissioner is hereby authorized to charge the above-referenced fees of \$0.00 and charge any additional fees or credit any overpayment associated with this communication to Deposit Account No. 08-1641 (Docket No. 26822-0002 P2).

Respectfully submitted,

Dated: September 8, 2003

By: 

Stacy Ann Hegle, Reg. No. 50,687

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<b>INFORMATION DISCLOSURE STATEMENT</b>  <b>PTO-1449</b>			ATTY. DOCKET NO. 26822-0002 P2		SERIAL NO. 10/092,936	
			APPLICANTS: RONG, Chang-Liang, et al.			
			FILING DATE: 03/06/2002		GROUP: 2873	
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,177,476 *	01/05/1993	Disanto et al.			
	5,872,552 *	02/16/1999	Gordon II et al.			
	4,655,897 *	04/07/1987	Disanto et al.			
	3,689,346 *	09/05/1972	Rowland			
	5,942,154 *	08/24/1999	Kim et al.			
	3,229,607 *	01/18/1966	Battaglia			
	5,877,848 *	03/02/1999	Gillette et al.			
	5,731,860 *	03/24/1998	Harada et al.			
	5,895,541 *	04/20/1999	Kobayashi et al.			
	5,985,084 *	11/16/1999	Summersgill et al.			
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	4,741,604 *	05/03/1988	Kornfeld			
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	5,274,481 *	12/28/1993	Kim			
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EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
	6,191,250 *	02/20/2001	Aida et al.				
	4,190,352 *	02/26/1980	Bruning				
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	5,285,236 *	02/08/1994	Jain				
	5,652,645 *	07/29/1997	Jain				
	5,398,041 *	03/14/1995	Hyatt				
	5,432,526 *	07/11/1995	Hyatt				
	5,995,190 *	11/30/1999	Nagae et al.				
	5,956,112 *	09/21/1999	Fujimori et al.				
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	6,018,383 *	01/25/2000	Dunn et al.				
	2001/0009352 *	07/26/2001	Moore				
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	20020126249 *	12/05/2002	Chan-Park, et al.				
	20020126249 *	09/12/2002	Liang, et al.				
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 1065553 *	Pub Date 01/03/2001	Europe (Ogawa)			<input type="checkbox"/>	<input type="checkbox"/>
	EP 0990942 *	Pub Date 04/05/2000	Europe (Yamanaka)			<input type="checkbox"/>	<input type="checkbox"/>
	EP 1195603 *	Pub Date 04/10/2002	Europe (Kawai)			<input type="checkbox"/>	<input type="checkbox"/>
	JP 6242423 *	Pub Date 09/02/1994	Japan (Nakai Yuichi) (English abstract included)			<input type="checkbox"/>	<input checked="" type="checkbox"/>

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY (Inventor)	CLASS	SUBCLASS	TRANSLATION
	JP 1-86116 *	Pub Date 01/26/1990	Japan (Seiichiro) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 60-205452 *	Pub Date 10/17/1985	Japan (Hisanori) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 2000 035677 *	Pub Date 02/02/2000	Japan (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 2000 075497 *	Pub Date 03/14/2000	Japan (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 2001 042118 *	Pub Date 02/16/2001	Japan (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 2001 056653 *	Pub Date 02/27/2001	Japan (Hayakawa) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	JP 02284126 *	Pub Date 11/21/1990	Japan (Oshiro) (English abstract included)			<input type="checkbox"/> <input checked="" type="checkbox"/>
	WO 97/04398 *	Pub Date 02/06/1997	PCT (Jacobson)			<input type="checkbox"/> <input type="checkbox"/>
	WO 01/67170 *	Pub Date 09/13/2001	PCT (Liang et al.)			<input type="checkbox"/> <input type="checkbox"/>
	WO 99/08151 *	Pub Date 02/18/1999	PCT ( Bruzzone et al.)			<input type="checkbox"/> <input type="checkbox"/>
	WO 00/03291 *	Pub Date 01/20/2000	PCT (Jacobson et al.)			<input type="checkbox"/> <input type="checkbox"/>
	WO 02/01281 *	Pub Date 01/03/2002	PCT (Liang et al.)			<input type="checkbox"/> <input type="checkbox"/>
	WO 99/53373 *	Pub Date 10/21/1999	PCT (Drzaic)			<input type="checkbox"/> <input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
	* Drzaic, P.S., "Liquid Crystal Dispersions" , The PDLC Paradigm, pp 1-9, (1995)					
	* Singer, B. "X-Y Addressable Electrophoretic Display", Proc. SID-18 (3/4): 255-266 (1977)					
	* Kazlas, P. et al., "SVGA Microencapsulated Electrophoretic Active Matrix Display for Information Applicances" <i>SID 01 Digest</i> 152-155 (2001)					
	* Bryning et al., "Reverse-Emulsion Electrophoretic Display (REED)" <i>SID 98 Digest</i> 1018-1021 (1998)					
	* Swanson et al., "High Performance Electrophoretic Displays" <i>SID 00 Digest</i> 29-31 (2000)					
	* Inoue, S. et al., "High Resolution Microencapsulated Electrophoretic Display (EPD) Driven by Poly-Si TFTs With Four-Level Grayscale" <i>IEEE Transactions on Electron Devices</i> 49(8):1532-1539 (2002)					
	* Matsuda Y. "Newly designed, high resolution, active matrix addressing in plane EPD" <i>IDW 02 EP2-3</i> 1341-1344 (2002)					

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	FILING DATE: 03/06/2002	GROUP: 2873
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>		
	* Ota et al., "Developments in Electrophoretic Displays" <i>Proc. of SID</i> 18:243-254 (1977)	
	* Kishi, E et al, "5.1 Development of In-Plane EPD", Canon Research Center, SID Digest, 2000, pp 24-27	
	USSN 09/606,654, "Manufacturing Process for Electrophoretic Display", filed 6/28/2000 (copy provided upon request)	
EXAMINER	DATE CONSIDERED	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*If an asterisk is placed beside the reference number, a copy is not provided because the reference was previously cited by or submitted to the PTO in a prior application that is identical in the statement and relied upon for an earlier filing date under 35 U.S.C. §120. 37 C.F.R. §1.98 (d).